

### **Design obfuscation versus test**

Farahmandi, Farimah; Sinanoglu, Ozgur; Blanton, Ronald; **Pagliarini, Samuel Nascimento** 2020 IEEE European Test Symposium (ETS) : ETS 2020, May 25 - 29, 2020, Tallinn, Estonia 2020 / 10 p <https://doi.org/10.1109/ETS48528.2020.9131590>

**RESCUE EDA Toolset for interdependent aspects of reliability, security and quality in nanoelectronic systems design**  
**Gürsoy, Cemil Cem**; Cardoso Medeiros, Guilherme; Chen, Juanho; **Balakrishnan, Aneesh**; Lai, Xinhui; Bagbaba, Ahmet Cagri; Raik, Jaan; Jenihhin, Maksim DATE 2019 2019 / 1 p. : ill <https://doi.org/10.5281/zenodo.3362529> <https://past.date-conference.com/>

### **RESCUE: interdependent challenges of reliability, security and quality in nanoelectronic systems**

**Jenihhin, Maksim; Raik, Jaan** 2020 Design, Automation & Test in Europe Conference & Exhibition (DATE), 9-13 March 2020, Grenoble, France : proceedings 2020 / art. 19690741 , 6 p <https://doi.org/10.23919/DAT48585.2020.9116558>